SILICON CARBIDE DIODES FOR ULTRA-HIGH DOSE RATE DOSIMETRY

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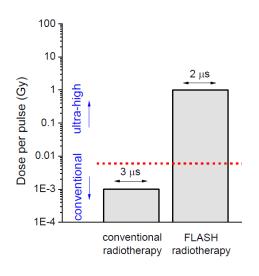
Context: FLASH radiotherapy

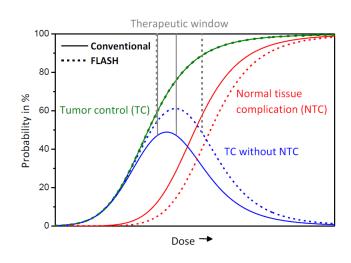
FLASH effect (Favaudon et al., Sci Transl Med 6 (2014)): Irradiations with con Ultra-High Dose Rate pulsed radiation reduce adverse effects in healthy tissues

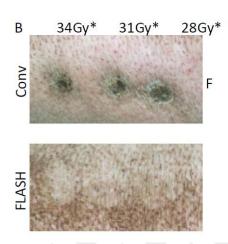
- Need real-time, highly precise dosimeters
- ➤ CNM is a partner in the European project EMPIR-UHDPulse (2019-2023) for metrology in UHDR beams









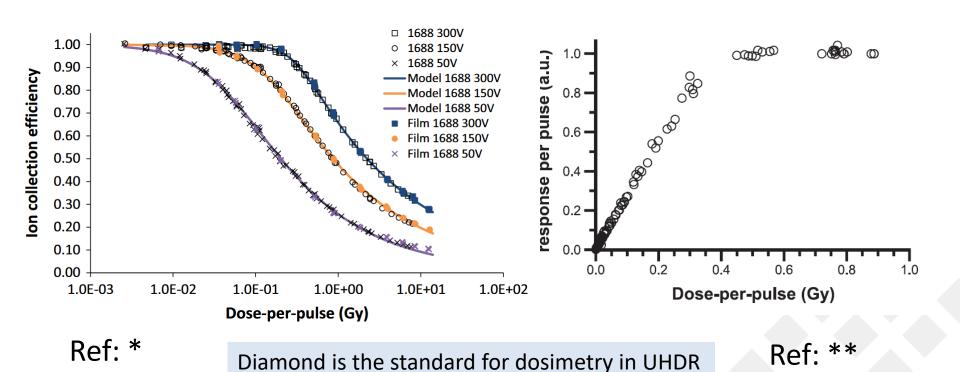








Limitation of conventional methods



URL: https://doi.org/10.1667/RADE-19-00012

^{*)} K. Petersson et al., High dose-per-pulse electron beam dosimetry — A model to correct for the ion recombination in the Advanced Markus ionization chamber, Med. Phys. 44 (3), March 2017

^{**)}Images from: E. Konradsson, et al., Correction for Ion Recombination in a Built-in Monitor Chamber of a Clinical Linear Accelerator at Ultra-High Dose Rates







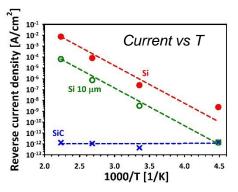
Silicon carbide diodes as real-time radiation dosimeters

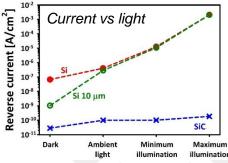
Why SiC? Wide bandgap semiconductors (SiC and diamond), compared to silicon, have:

- Lower dark current
- Higher radiation hardness
- Tolerance to visible light and temperature variations

In addition, SiC compared to diamond has:

- More mature technology allowing to produce complex structures
- High quality substrate material available up to 200 mm wafers at a reasonable cost: good price-performance ratio





J. M. Rafí et al. JINST 13 C01045 (2018); IEEE Trans.Nucl.Sci. 67 (2020)

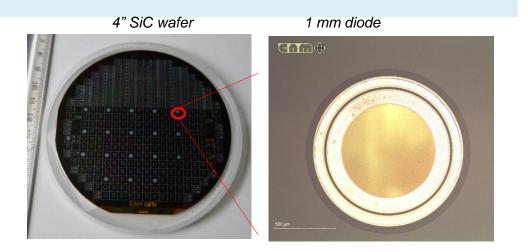




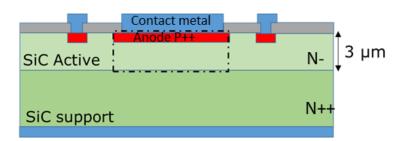


Devices (dosimeter)

- Circular 1 mm diameter PiN diodes on 3μm epitaxial 4H-SiC
- Designed and fabricated by IMB-CNM-CSIC (EU Patent pending)
- Encapsulated by PTW with their microSilicon housing for electrical connectivity



SiC diode schematic cross section



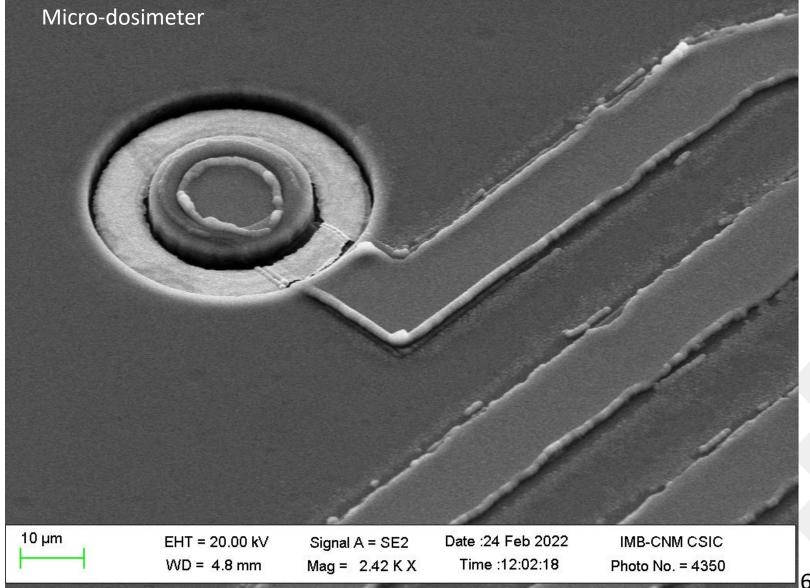
Encapsulated for electrical connectivity and for testing in water











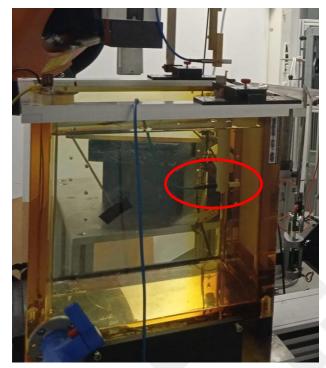






Electron tests at PTB

- Measurements at PTB UHDPP¹ electron beam
- Electron energy 20 MeV
- Repetition rate 5 Hz, pulse duration 0.6, 1.6 and 2.9 μs
- Measurements in PMMA water tank with a motorized positioning system
- Reference dosimetry provided by Alanine and prototype flashDiamond²
- SiC diode operated without external bias



SiC diode in water phantom at PTB

^{1.} Physikalisch-Technische Bundesanstalt (PTB), Braunschweig, Germany

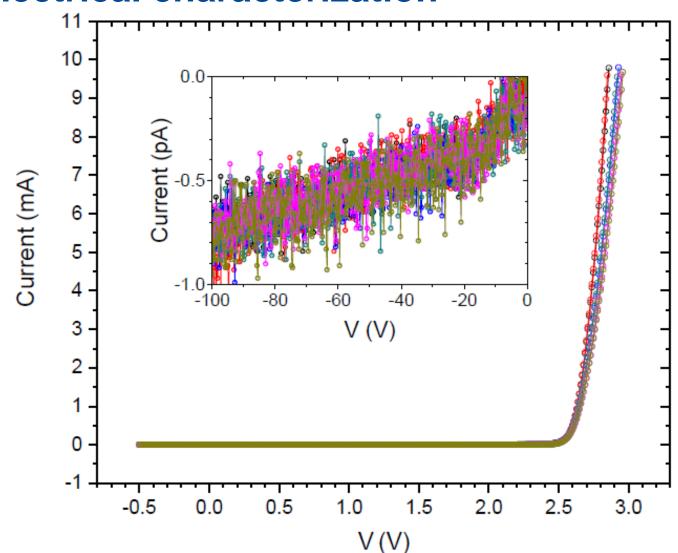
^{2.} M. Marinelli et al. "Design, realization and characterization of a novel diamond detector prototype for FLASH radiotherapy dosimetry" Med Phys. 2022;49:1902–1910







Electrical characterization





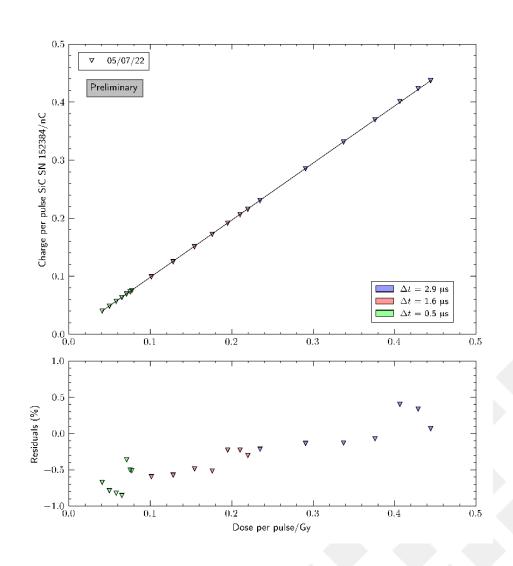




Results

Intermediate Dose Per Pulse (DPP) range: 0.42 Gy

- Response independent both of DPP and of instantaneous dose rate
- Linearity deviation < 1 % *
- SiC diode sensitivity ~1 nC/Gy





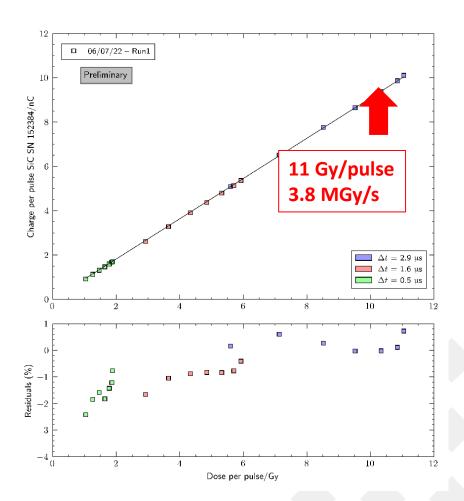




Results (UHDR)

Ultra-high Dose Per Pulse (DPP) range: 11 Gy

 Signal linearity up to at least 11 Gy/pulse with a relative deviation of < 3 %





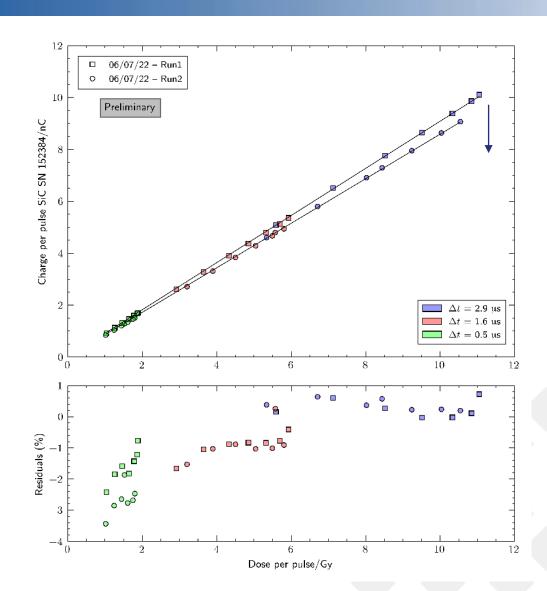




Results

Effect of accumulated dose

- Two runs, around ~26 kGy accumulated dose between them
- Response linearity not affected
- 5% reduction in sensitivity
- The saturation of the device response is associated to the series resistance –
- The higher the series resistance the lower the DPP value up to which the detector shows a linear response.

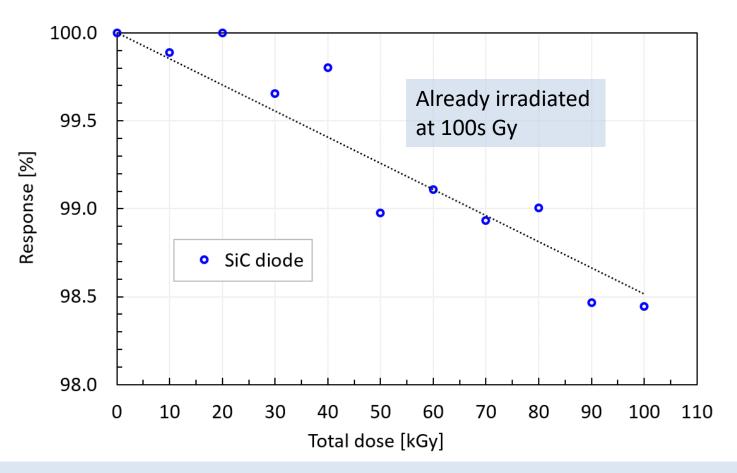








Pre-Irradiation



If pre-irradiated the sensibility of SiC its response is less sensible to variation



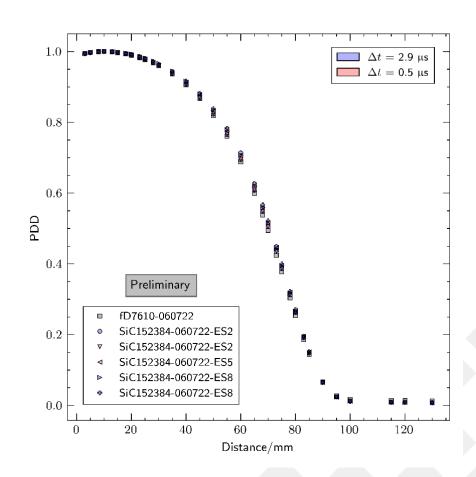




Results

Depth Dose Curves PDD measurement

- Several runs of PDD curves performed under UHDPP conditions with different dose per pulse and pulse duration irradiations
- SiC diode performance comparable to reference flashDiamond









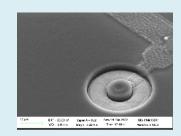
Conclusions and outlook

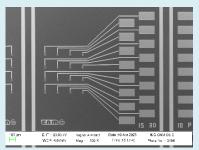
First SiC diodes for relative dosimetry in UHDR pulsed electron beams.

- ✓ Response independent both of DPP and of instantaneous dose rate in the investigated range: up to 11 Gy/pulse, 3.8 MGy/s
- ✓ Radiation robust: 5% sensitivity reduction over 26 kGy
- ✓ Performance comparable to flashDiamond in PDD measurement

Future work:

- Systematic characterization in a wide range of beam configurations
- Validation of other detector structures fabricated: diodes with sidewalls removed for increased spatial and dose resolution, pixel configurations for 2D dose maps
- Understand the radiation hardness of SiC in different beams.
- Fabricate a new active dosimetry monitor based on the development of innovative SiC microdetectors able to quantify the dose delivered in FLASH effect in two dimensions.









Thank you for your attention

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Disclosure

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